

SLOVENSKI STANDARD

SIST EN 62435-2:2017

01-junij-2017

Elektronske komponente - Dolgoročno skladiščenje elektronskih polprevodniških elementov - 2. del: Mehanizmi slabšanja (IEC 62435-2:2017)

Electronic components - Long-term storage of electronic semiconductor devices - Part 2 - Deterioration Mechanisms (IEC 62435-2:2017)

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Composants électroniques - Stockage de longue durée des dispositifs électroniques à semiconducteurs - Partie 2 - Mécanismes de détérioration (IEC 62435-2:2017)

[SIST EN 62435-2:2017](https://standards.iteh.ai/catalog/standards/sist/cce49325-e7c6-4ccf-96f3-6c3a45170b24/sist-en-62435-2-2017)

Ta slovenski standard je istoveten z: EN 62435-2:2017

ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 62435-2

April 2017

ICS 31.020

English Version

**Electronic components - Long-term storage of electronic
semiconductor devices - Part 2: Deterioration mechanisms
(IEC 62435-2:2017)**

Composants électroniques - Stockage de longue durée des
dispositifs électroniques à semiconducteurs -
Partie 2: Mécanismes de détérioration
(IEC 62435-2:2017)

Elektronische Bauteile - Langzeitlagerung elektronischer
Halbleiterbauelemente - Teil 2: Schädigungsmechanismen
(IEC 62435-2:2017)

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SIST EN 62435-2:2017

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 62435-2:2017**European foreword**

The text of document 47/2327/FDIS, future edition 1 of IEC 62435-2, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62435-2:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-11-28
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-02-28

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IEC 60068-2-17:1994	NOTE	Harmonized as EN 60068-2-17:1994 (not modified).
IEC 60068-2-20:2008	NOTE	Harmonized as EN 60068-2-20:2008 (not modified).
IEC 60721-3-1	NOTE	Harmonized as EN 60721-3-1.
IEC 60721-3-3	NOTE	Harmonized as EN 60721-3-3.
IEC 60749-21	NOTE	Harmonized as EN 60749-21.
IEC 61340-5-1:2007	NOTE	Harmonized as EN 61340-5-1:2007 (not modified).
IEC/TR 61340-5-2:2007	NOTE	Harmonized as CLC/TR 61340-5-2:2008 (not modified).
IEC 61760-4	NOTE	Harmonized as EN 61760-4.
IEC/TR 62258-3	NOTE	Harmonized as CLC/TR 62258-3.
IEC 62435-1	NOTE	Harmonized as EN 62435-1.
IEC 62435-4 ¹⁾	NOTE	Harmonized as EN 62435-4 ¹⁾ .
IEC 62435-5	NOTE	Harmonized as EN 62435-5.

1) At draft stage.

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-20-1	-	Semiconductor devices - Mechanical and climatic test methods - Part 20-1: Handling, packing, labelling and shipping of surface-mount devices sensitive to the combined effect of moisture and soldering heat	EN 60749-20-1	-

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Edition 1.0 2017-01

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Electronic components – Long-term storage of electronic semiconductor devices –
Part 2: Deterioration mechanisms**

**Composants électroniques – Stockage de longue durée des dispositifs électroniques à semiconducteurs –
Partie 2: Mécanismes de détérioration**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTRONIC COMPONENTS – LONG-TERM STORAGE
OF ELECTRONIC SEMICONDUCTOR DEVICES –****Part 2: Deterioration mechanisms****FOREWORD**

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International Standard IEC 62435-2 has been prepared by IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/2327/FDIS	47/2350/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62435 series, published under the general title *Electronic components – Long-term storage of electronic semiconductor devices*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

This document applies to the long-term storage of electronic components.

This is a document for long-term storage (LTS) of electronic devices drawing on the best long-term storage practices currently known. For the purposes of this document, LTS is defined as any device storage whose duration can be more than 12 months for product scheduled for long duration storage. While intended to address the storage of unpackaged semiconductors and packaged electronic devices, nothing in this standard precludes the storage of other items under the storage levels defined herein.

Although it has always existed to some extent, obsolescence of electronic components and particularly of integrated circuits, has become increasingly intense over the last few years.

Indeed, with the existing technological boom, the commercial life of a component has become very short compared with the life of industrial equipment such as that encountered in the aeronautical field, the railway industry or the energy sector.

The many solutions enabling obsolescence to be resolved are now identified. However, selecting one of these solutions should be preceded by a case-by-case technical and economic feasibility study, depending on whether storage is envisaged for field service or production, for example:

- remedial storage as soon as components are no longer marketed;
- preventive storage anticipating declaration of obsolescence.

Taking into account the expected life of some installations, sometimes covering several decades, the qualification times, and the unavailability costs, which can also be very high, the solution to be adopted to resolve obsolescence should often be rapidly implemented. This is why the solution retained in most cases consists in systematically storing components which are in the process of becoming obsolescent.

The technical risks of this solution are, a priori, fairly low. However, it requires perfect mastery of the implemented process and especially of the storage environment, although this mastery becomes critical when it comes to long-term storage.

All handling, protection, storage and test operations are recommended to be performed according to the state of the art.

The application of the approach proposed in this standard in no way guarantees that the stored components are in perfect operating condition at the end of this storage. It only comprises a means of minimizing potential and probable degradation factors.

Some electronic device users have the need to store electronic devices for long periods of time. Lifetime buys are commonly made to support production runs of assemblies that well exceed the production timeframe of its individual parts. This puts the user in a situation requiring careful and adequate storage of such parts to maintain the as-received solderability and minimize any degradation effects to the part over time. Major degradation concerns are moisture, electrostatic fields, ultra-violet light, large variations in temperature, air-borne contaminants, and outgassing.

Warranties and sparing also present a challenge for the user or repair agency as some systems have been designated to be used for long periods of time, in some cases for up to 40 years or more. Some of the devices needed for repair of these systems will not be available from the original supplier for the lifetime of the system or the spare assembly may be built with the original production run but then require long-term storage. This document was developed to provide a standard for storing electronic devices for long periods of time.